

## 40V Dual N-Channel Power MOSFET

### Product Summary

$V_{DS}$	$R_{DS(ON),MAX}$	$I_{D\_MAX}$
40 V	5.5 m $\Omega$ @ $V_{GS} = 10V$	68 A

### Features

- N-Channel Enhancement Mode - Standard Level
- AEC-Q101 Qualified, PPAP Capable
- 175°C Operating Temperature
- 100% UIS and  $R_g$  Tested
- AEC-Q101 qualified (Automotive grade with suffix "Q".)
- Exsemi technology

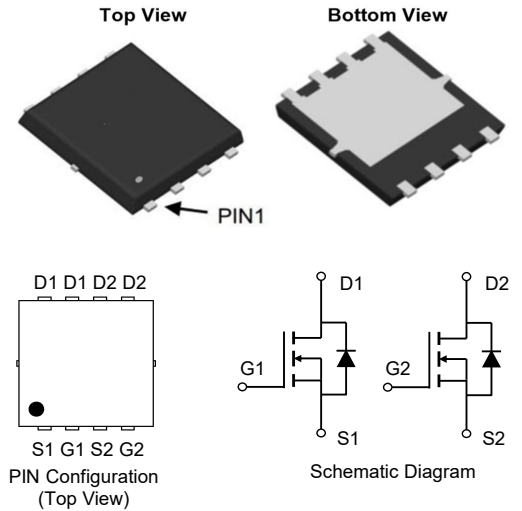
### Applications

- General Automotive Applications

### Mechanical Data

- Green Molding Compound
- Moisture Sensitivity: Level 1 per J-STD-020
- UL Flammability Classification Rating 94V-0

### PDFN5060-8L



### Ordering Information

Orderable Part Number	Package Type	Device Marking	Form	Quantity (pcs)
EPT04ND055HCFQ	PDFN5060-8L	4005AHDQ	13" Tape&Reel	5,000

### Maximum Ratings (@ $T_C = 25^\circ\text{C}$ , unless otherwise specified.)

Parameter	Symbol	Value	Unit
Drain - Source Voltage	$V_{DS}$	40	V
Gate - Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current ( $V_{GS} = 10V$ ) <sup>(1)</sup>	$T_C = 25^\circ\text{C}$	68	A
	$T_C = 100^\circ\text{C}$	48	A
Pulsed Drain Current <sup>(2)</sup>	$I_{DM}$	264	A
Single Pulse Avalanche Energy <sup>(3)</sup>	$E_{AS}$	116	mJ
Single Pulse Avalanche Current ( $L = 0.1\text{mH}$ )	$I_{AS}$	28	A
Power Dissipation	$T_C = 25^\circ\text{C}$	44	W
	$T_C = 100^\circ\text{C}$	22	W
Junction & Storage Temperature Range	$T_J, T_{STG}$	-55 ~ +175	$^\circ\text{C}$

### Thermal Characteristics

Parameter	Symbol	Typ.	Max.	Unit
Thermal Resistance, Junction-to-Ambient <sup>(4)</sup>	$R_{\theta JA}$	45	56	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Case <sup>(5)</sup>	$R_{\theta JC}$	2.6	3.4	$^\circ\text{C/W}$

**Electrical Characteristics** (@  $T_J = 25^\circ\text{C}$ , unless otherwise specified.)

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b> <sup>(6)</sup>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 40V, V_{GS} = 0V$ $T_J = 125^\circ\text{C}$	-	-	1.0	$\mu A$
			-	-	100	$\mu A$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
<b>On Characteristics</b> <sup>(6)</sup>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	2.0	3.0	4.0	V
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 20A$	-	4.6	5.5	m $\Omega$
Forward Transconductance	$g_{fs}$	$V_{DS} = 5.0V, I_D = 20A$	-	15	-	S
Diodes Forward Voltage	$V_{SD}$	$I_S = 2.0A, V_{GS} = 0V$	-	0.7	1.2	V
<b>Dynamic Characteristics</b> <sup>(7)</sup>						
Input Capacitance	$C_{iss}$	$V_{DS} = 20V, V_{GS} = 0V, f = 1MHz$	-	982	-	pF
Output Capacitance	$C_{oss}$		-	593	-	pF
Reverse Transfer Capacitance	$C_{rss}$		-	25	-	pF
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	-	4.2	-	$\Omega$
<b>Switching Characteristics</b> <sup>(7)</sup>						
Turn-On DelayTime	$t_{d(on)}$	$V_{GS} = 10V, V_{DS} = 20V$ $I_D = 20A, R_{GEN} = 3.0\Omega$	-	5.7	-	ns
Rise Time	$t_r$		-	11	-	ns
Turn-Off DelayTime	$t_{d(off)}$		-	14	-	ns
Fall Time	$t_f$		-	8.0	-	ns
<b>Gate Charge Characteristics</b> <sup>(7)</sup>						
Total Gate Charge ( $V_{GS} = 10V$ )	$Q_g$	$V_{DS} = 20V, I_D = 20A$ $V_{GS} = 10V$	-	14	-	nC
Total Gate Charge ( $V_{GS} = 6.0V$ )	$Q_g$		-	8.7	-	nC
Gate-Source Charge	$Q_{gs}$		-	4.6	-	nC
Gate-Drain Charge	$Q_{gd}$		-	2.9	-	nC
Gate Plateau Voltage	$V_{plateau}$		-	5.2	-	V
<b>Drain-Source Diode Characteristics</b> <sup>(7)</sup>						
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = 20A, di/dt = 100A/\mu s,$ $T_J = 25^\circ\text{C}$	-	30	-	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$		-	13	-	nC
Diode Forward Current	$I_S$	$T_C = 25^\circ\text{C}$	-	-	57	A

**Notes:**

- This current is chip limited, which is calculated based on  $R_{thjc}$ .
- This current is calculated on single pulse with 10 $\mu s$  Pulse & Duty Cycle = 1%.
- Defined by design, not subject to production test,  $E_{AS}$  condition:  $T_J = 25^\circ\text{C}, V_{DD} = 20V, V_{GS} = 10V, L = 1.0mH$ .
- Device mounted on FR-4 substrate PC board with 2oz copper in 1inch square cooling area.
- Thermal resistance from junction to soldering point (on the exposed drain pad).
- Short duration pulse test used to minimize self-heating effect.
- Defined by design, not subject to production.

Typical Electrical and Thermal Characteristics

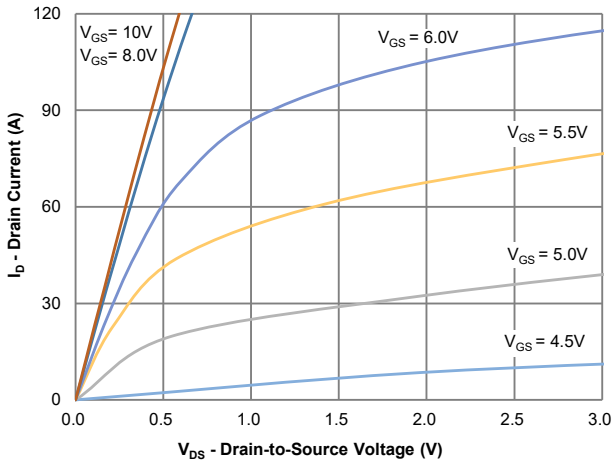


Figure 1: Output Characteristics

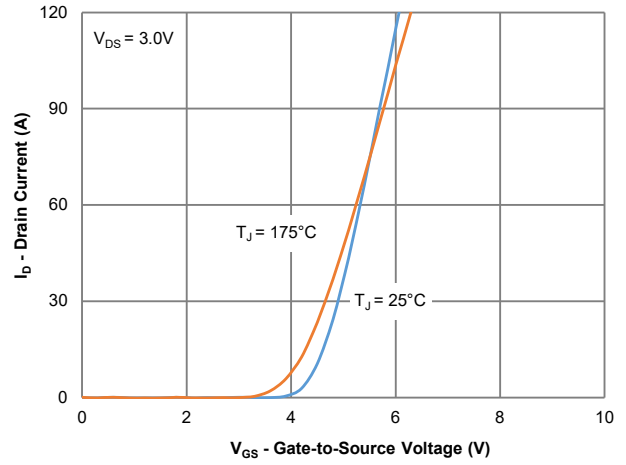


Figure 2: Transfer Characteristics

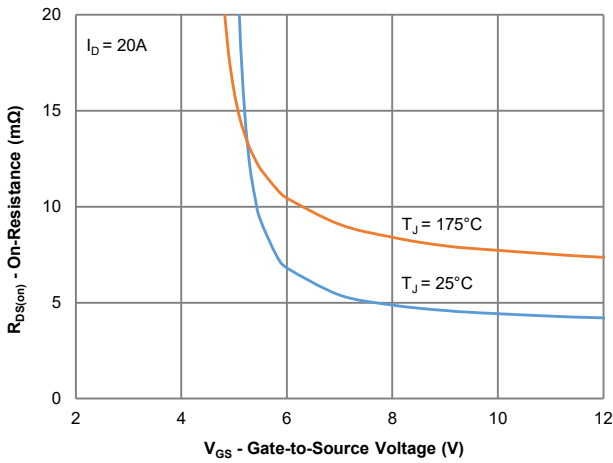


Figure 3: On-Resistance vs. Gate-Source Voltage

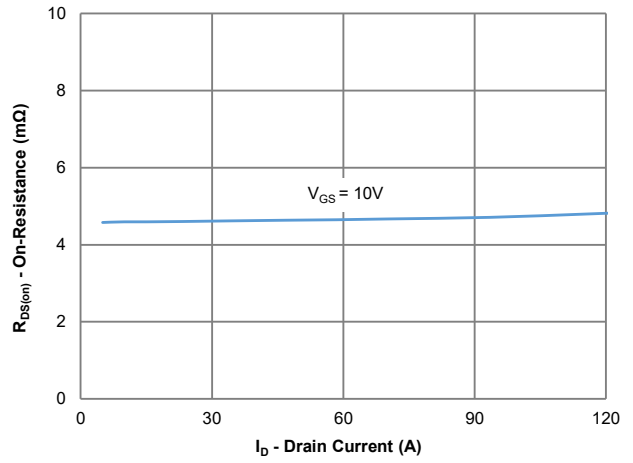


Figure 4: On-Resistance vs. Drain Current

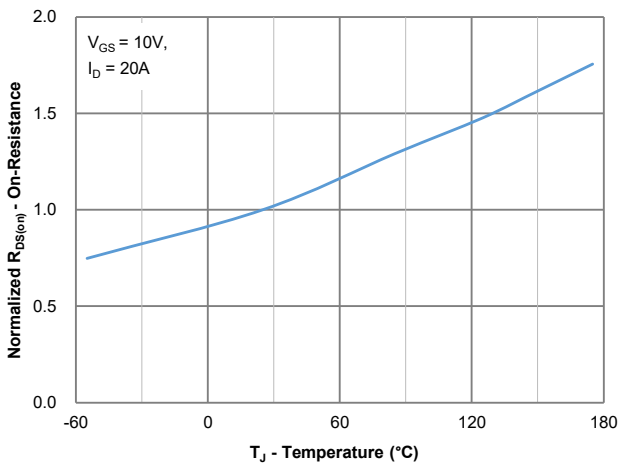


Figure 5: On-Resistance vs. Junction Temperature

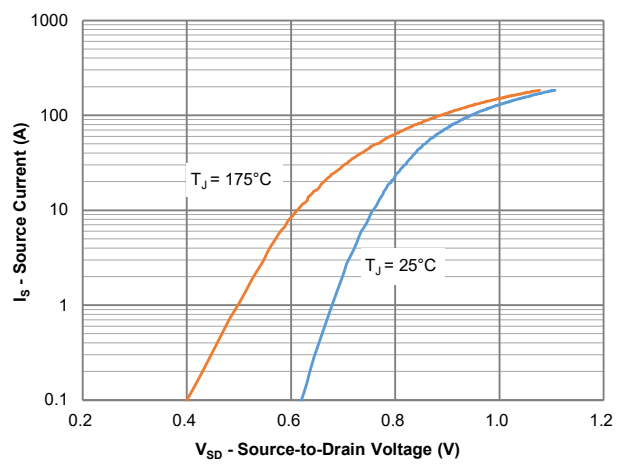


Figure 6: Source-Drain Diode Forward Voltage

Typical Electrical and Thermal Characteristics

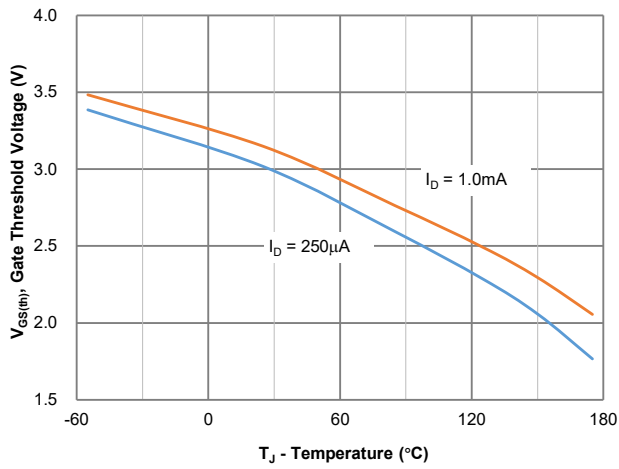


Figure 7: Gate Threshold Variation vs. Junction Temperature

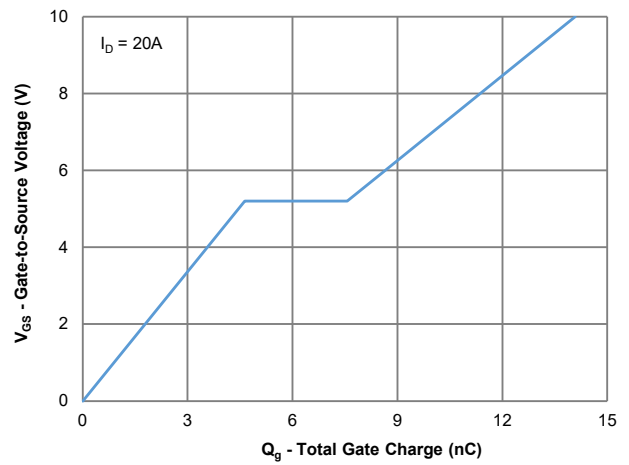


Figure 8: Gate Charge Characteristics

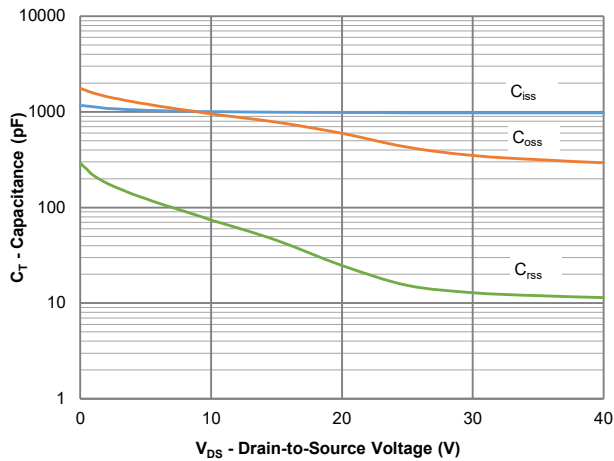


Figure 9: Capacitance Characteristics

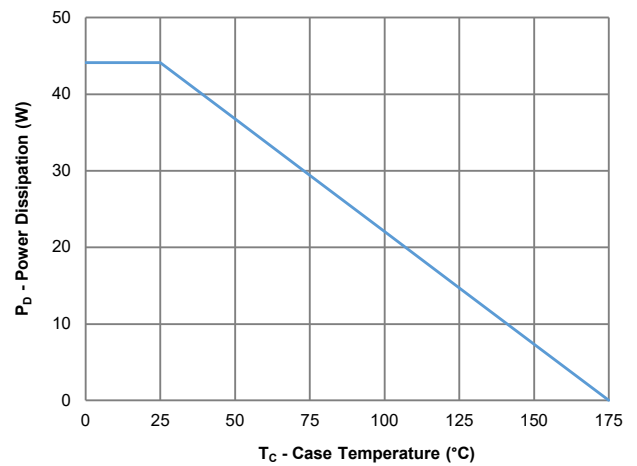


Figure 10: Power Derating

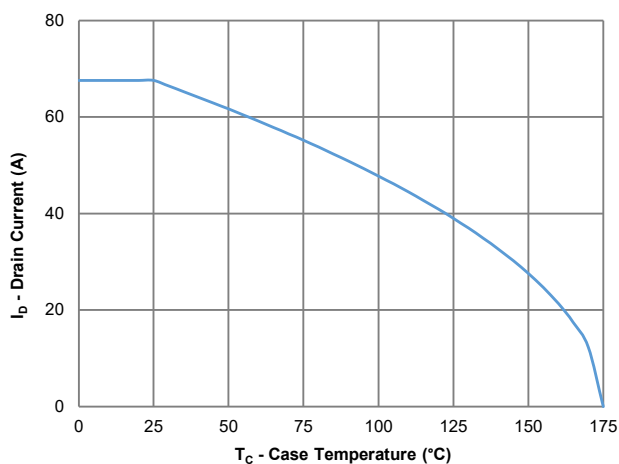


Figure 11: Current Derating

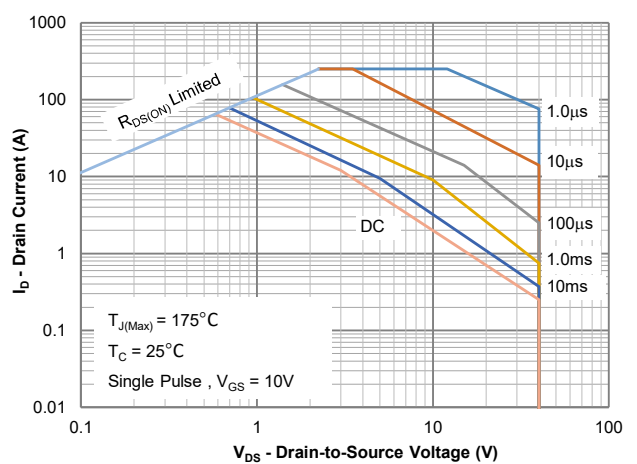


Figure 12: Safe Operating Area

Typical Electrical and Thermal Characteristics

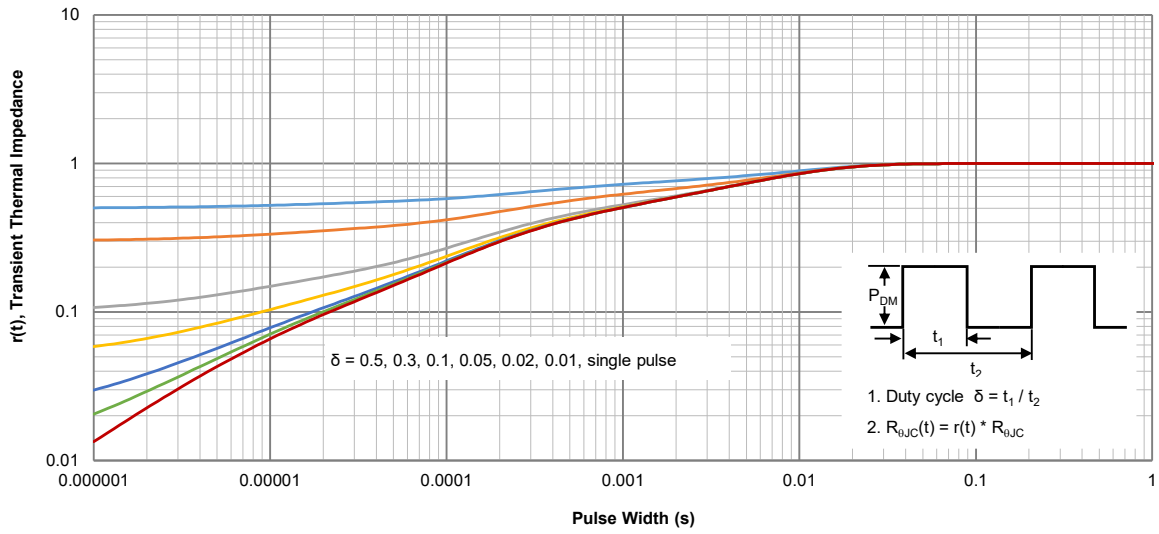
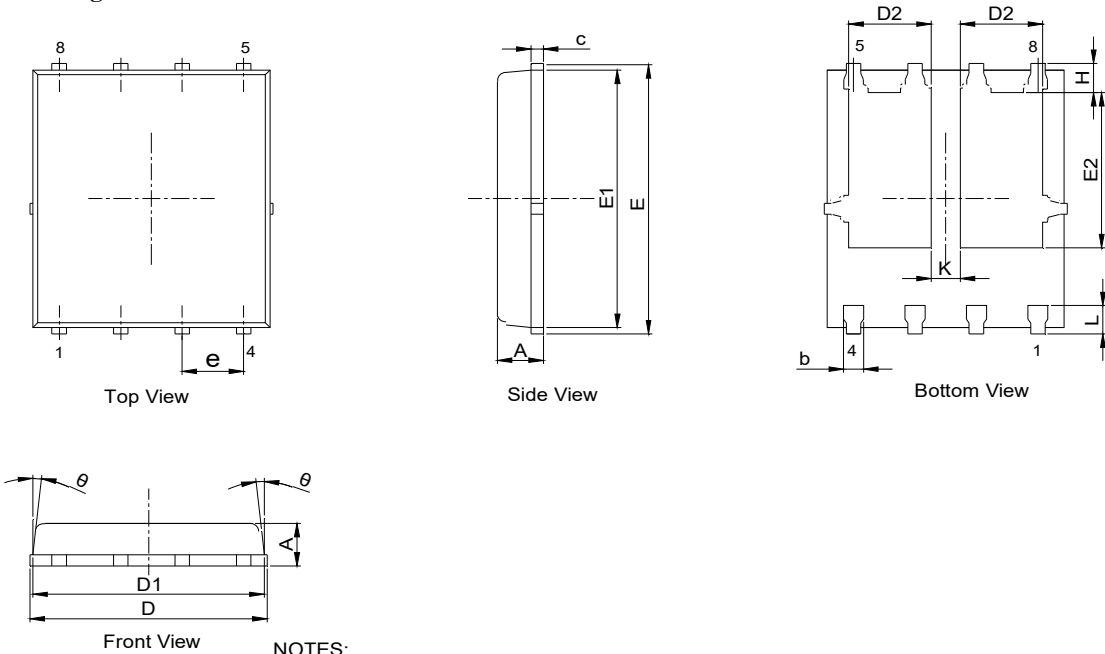


Figure 13: Normalized Maximum Transient Thermal Impedance

PDFN5060-8L Package Outline

Package Outline

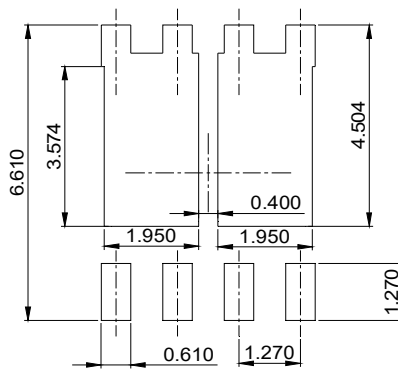


NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M,1994.
2. ALL DIMNESIONS IN MILLIMETER (ANNGLE IN DEGREE).
3. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

DIM.	MILLIMETER		
	MIN.	NOM.	MAX.
A	0.90	1.00	1.10
b	0.20	--	0.51
c	0.21	0.25	0.34
D	4.90	5.00	5.15
D1	4.80	4.90	5.00
D2	1.50	--	1.80
E	5.90	6.00	6.10
E1	5.65	5.75	5.85
E2	3.38	3.48	3.78
e	1.27BSC		
H	0.41	--	0.75
L	0.45	0.60	0.75
K	0.60 REF		
theta	0°	--	12°

Recommended Soldering Footprint



DIMENSIONS: MILLIMETERS